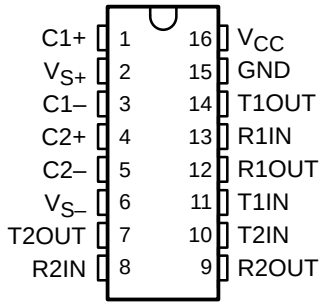
- **Meet or Exceed TIA/EIA-232-F and ITU Recommendation V.28**
- **Operate With Single 5-V Power Supply**
- **Operate Up to 120 kbit/s**
- **Two Drivers and Two Receivers**
- **±30-V Input Levels**
- **Low Supply Current . . . 8 mA Typical**
- **Designed to be Interchangeable With Maxim MAX232**
- **ESD Protection Exceeds JESD 22**
  – 2000-V Human-Body Model (A114-A)
- **Applications**
  - **TIA/EIA-232-F**
  - **Battery-Powered Systems**
  - **Terminals**
  - **Modems**
  - **Computers**

MAX232 . . . D, DW, N, OR NS PACKAGE
MAX232I . . . D, DW, OR N PACKAGE
(TOP VIEW)



description/ordering information

The MAX232 is a dual driver/receiver that includes a capacitive voltage generator to supply EIA-232 voltage levels from a single 5-V supply. Each receiver converts EIA-232 inputs to 5-V TTL/CMOS levels. These receivers have a typical threshold of 1.3 V and a typical hysteresis of 0.5 V, and can accept ±30-V inputs. Each driver converts TTL/CMOS input levels into EIA-232 levels. The driver, receiver, and voltage-generator functions are available as cells in the Texas Instruments LinASIC™ library.

ORDERING INFORMATION

T_A	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
0°C to 70°C	PDIP (N)	Tube	MAX232N	MAX232N
	SOIC (D)	Tube	MAX232D	MAX232
		Tape and reel	MAX232DR	
	SOIC (DW)	Tube	MAX232DW	MAX232
		Tape and reel	MAX232DWR	
	SOP (NS)	Tape and reel	MAX232NSR	MAX232
–40°C to 85°C	PDIP (N)	Tube	MAX232IN	MAX232IN
	SOIC (D)	Tube	MAX232ID	MAX232I
		Tape and reel	MAX232IDR	
	SOIC (DW)	Tube	MAX232IDW	MAX232I
		Tape and reel	MAX232IDWR	

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

Function Tables

EACH DRIVER

INPUT TIN	OUTPUT TOUT
L	H
H	L

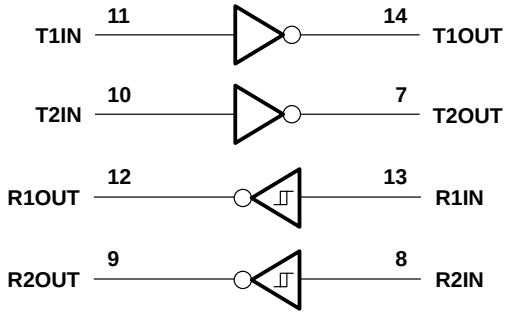
H = high level, L = low level

EACH RECEIVER

INPUT RIN	OUTPUT ROUT
L	H
H	L

H = high level, L = low level

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Input supply voltage range, V_{CC} (see Note 1) . . . . . –0.3 V to 6 V
Positive output supply voltage range, V_{S+} . . . . . V_{CC} – 0.3 V to 15 V
Negative output supply voltage range, $V_{S–}$ . . . . . –0.3 V to –15 V
Input voltage range, V_I: Driver . . . . . –0.3 V to V_{CC} + 0.3 V
Receiver . . . . . ±30 V
Output voltage range, V_O: T1OUT, T2OUT . . . . . $V_{S–}$ – 0.3 V to V_{S+} + 0.3 V
R1OUT, R2OUT . . . . . –0.3 V to V_{CC} + 0.3 V
Short-circuit duration: T1OUT, T2OUT . . . . . Unlimited
Package thermal impedance, θ_{JA} (see Note 2): D package . . . . . 73°C/W
DW package . . . . . 57°C/W
N package . . . . . 67°C/W
NS package . . . . . 64°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds . . . . . 260°C
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to network ground terminal.
2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage		4.5	5	5.5	V
V_{IH}	High-level input voltage (T1IN,T2IN)		2			V
V_{IL}	Low-level input voltage (T1IN, T2IN)				0.8	V
R1IN, R2IN	Receiver input voltage				±30	V
T_A	Operating free-air temperature	MAX232	0		70	°C
		MAX232I	–40		85	

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 4)

PARAMETER		TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
I_{CC}	Supply current	V_{CC} = 5.5 V, All outputs open, T_A = 25°C		8	10	mA

‡ All typical values are at V_{CC} = 5 V and T_A = 25°C.

NOTE 3: Test conditions are C1–C4 = 1 μF at V_{CC} = 5 V ± 0.5 V.

DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature range (see Note 3)

PARAMETER			TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{OH}	High-level output voltage	T1OUT, T2OUT	R_L = 3 kΩ to GND		5	7		V
V_{OL}	Low-level output voltage‡	T1OUT, T2OUT	R_L = 3 kΩ to GND			–7	–5	V
r_o	Output resistance	T1OUT, T2OUT	$V_{S+} = V_{S-} = 0$,	V_O = ±2 V	300			Ω
I_{OS}§	Short-circuit output current	T1OUT, T2OUT	V_{CC} = 5.5 V,	V_O = 0		±10		mA
I_{IS}	Short-circuit input current	T1IN, T2IN	V_I = 0				200	μA

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic voltage levels only.
§ Not more than one output should be shorted at a time.
NOTE 3: Test conditions are C1–C4 = 1 μF at V_{CC} = 5 V ± 0.5 V.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see Note 3)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SR	Driver slew rate	R_L = 3 kΩ to 7 kΩ, See Figure 2			30	V/μs
SR(t)	Driver transition region slew rate	See Figure 3		3		V/μs
	Data rate	One TOUT switching		120		kbit/s

NOTE 3: Test conditions are C1–C4 = 1 μF at V_{CC} = 5 V ± 0.5 V.

RECEIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature range (see Note 3)

PARAMETER			TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{OH}	High-level output voltage	R1OUT, R2OUT	I_{OH} = –1 mA		3.5			V
V_{OL}	Low-level output voltage‡	R1OUT, R2OUT	I_{OL} = 3.2 mA				0.4	V
V_{IT+}	Receiver positive-going input threshold voltage	R1IN, R2IN	V_{CC} = 5 V,	T_A = 25°C		1.7	2.4	V
V_{IT-}	Receiver negative-going input threshold voltage	R1IN, R2IN	V_{CC} = 5 V,	T_A = 25°C	0.8	1.2		V
V_{hys}	Input hysteresis voltage	R1IN, R2IN	V_{CC} = 5 V		0.2	0.5	1	V
r_i	Receiver input resistance	R1IN, R2IN	V_{CC} = 5,	T_A = 25°C	3	5	7	kΩ

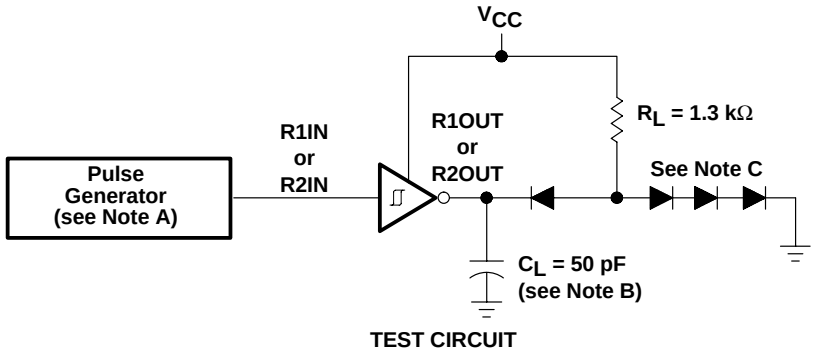
† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic voltage levels only.
NOTE 3: Test conditions are C1–C4 = 1 μF at V_{CC} = 5 V ± 0.5 V.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see Note 3 and Figure 1)

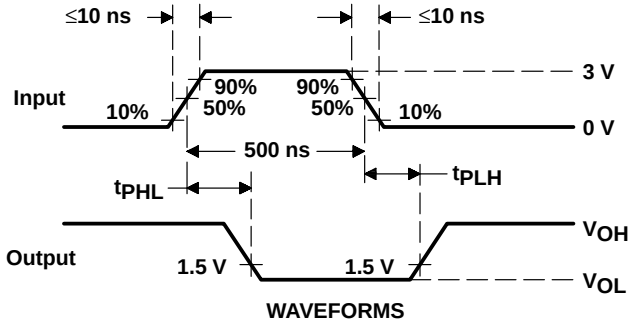
PARAMETER		TYP	UNIT
$t_{PLH(R)}$	Receiver propagation delay time, low- to high-level output	500	ns
$t_{PHL(R)}$	Receiver propagation delay time, high- to low-level output	500	ns

NOTE 3: Test conditions are C1–C4 = 1 μF at V_{CC} = 5 V ± 0.5 V.

PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT

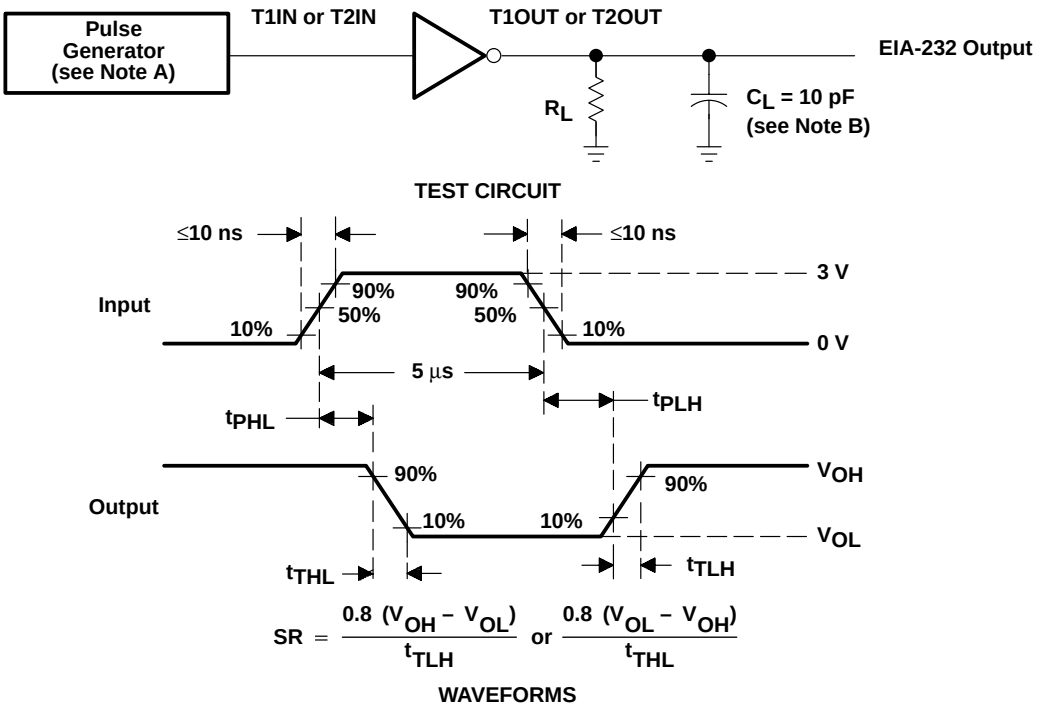


WAVEFORMS

NOTES: A. The pulse generator has the following characteristics: Z_O = 50 Ω, duty cycle ≤ 50%.
B. C_L includes probe and jig capacitance.
C. All diodes are 1N3064 or equivalent.

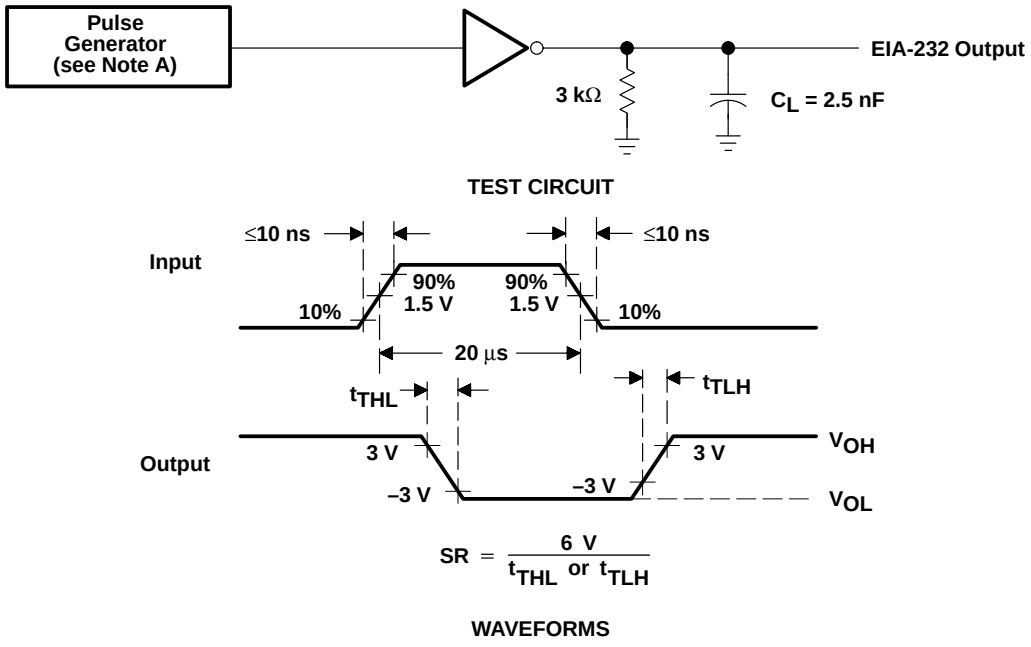
Figure 1. Receiver Test Circuit and Waveforms for t_{PHL} and t_{PLH} Measurements

PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: Z_O = 50 Ω, duty cycle ≤ 50%.
B. C_L includes probe and jig capacitance.

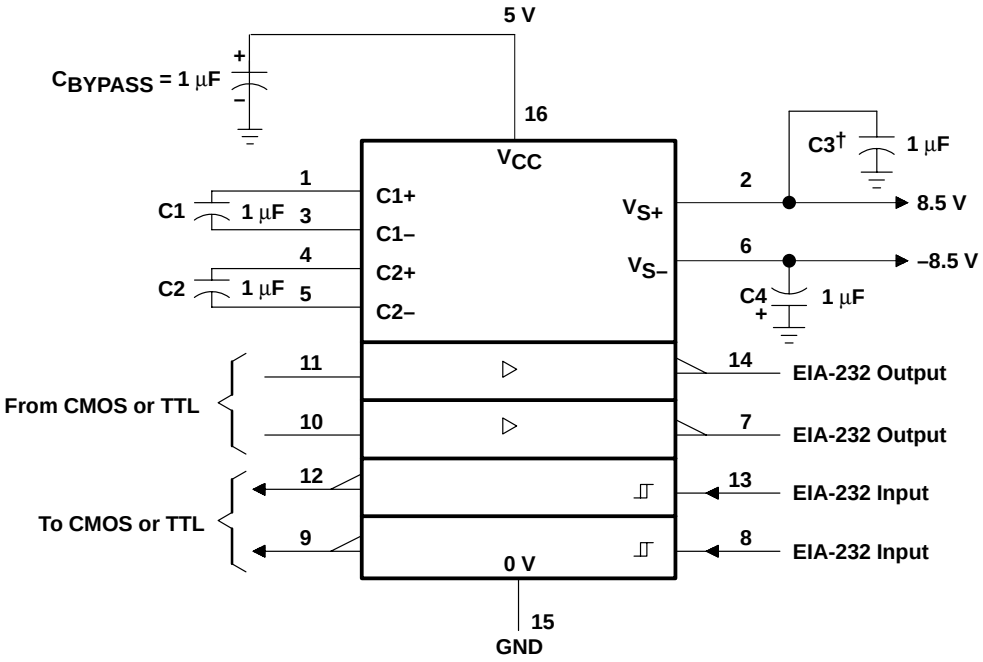
Figure 2. Driver Test Circuit and Waveforms for t_{PHL} and t_{PLH} Measurements (5-μs Input)



NOTE A: The pulse generator has the following characteristics: Z_O = 50 Ω, duty cycle ≤ 50%.

Figure 3. Test Circuit and Waveforms for t_{THL} and t_{TLH} Measurements (20-μs Input)

APPLICATION INFORMATION



† C3 can be connected to V_{CC} or GND.

Figure 4. Typical Operating Circuit

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